

Form PTO-1449

Sheet 1 of 2

Applicant: Ryuzo Iga et al.

Confirmation No.: 9935

Serial No.: 10/577,626

Att'y Docket No.: 14321.84

Filing Date: April 28, 2006

Art Unit: 2828

For: SEMICONDUCTOR OPTICAL DEVICE AND A METHOD OF FABRICATING THE SAME

INFORMATION DISCLOSURE CITATIONS MADE BY APPLICANTU.S. Patent Documents

| <u>Examiner Initial*</u> | <u>Document Number</u> | <u>Issue Date</u> | <u>Name</u> |
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Examiner: /Patrick Stafford/

Date Considered: 07/08/2008

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Examiners will consider all citations submitted in conformance with 37 C.F.R. § 1.98 and MPEP Sec. 609 and place their initials adjacent the citations in the spaces provided on this form. Examiners will also initial citations not in conformance with the guidelines which may have been considered. A reference may be considered by the Examiner for any reason whether or not the citation is in full conformance with the guidelines. A line will be drawn through a citation if it is not in conformance with the guidelines AND has not been considered. A copy of the submitted form, as reviewed by the Examiner, will be returned to the applicant with the next communication. The original of the form will be entered into the application file.

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